## Applicant(s)/Patent Under Application/Control No. Reexamination 10/041,685 SUEMATSU ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1734 Yewebdar T Tadesse **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name MM-YYYY Country Code-Number-Kind Code 385/78 07-2001 Ohtsuka et al. US-6,264,375 Α 264/1.25 01-2002 Yang, Hsi-Harng В US-6,342,170 385/78 Ueno et al. 02-2002 US-6,347,890 С US-D US-Ε F US-G US-USн US-US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Date Document Number Classification Name Country MM-YYYY Country Code-Number-Kind Code Ν 0 Р Q R S Т NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х